Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/464,322	KWON ET AL.
Examiner	Art Unit
Chris C. Chu	2815

SEARCHED				
Class	Subclass	Date	Examiner	
257	E23.103, 678, 720, 706 & 707	11/7/2006	C.C.	
257	778 & 722	11/7/2006	C.C.	
257	712 & 704	11/7/2006	C.C.	
438	122	11/7/2006	C.C.	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	11/7/2006	C.C.
Consulted withS. Clark 257/706, 707, 778 & 722	3/26/2001	C.C.
Consulted with Jerome Jackson	12/5/2001	C.C.
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